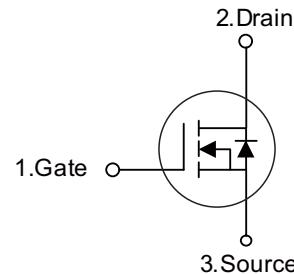


## ■ PRODUCT CHARACTERISTICS

VDSS	30V
R <sub>DS(on)</sub> max(@V <sub>GS</sub> = 4.5 V)	5.6mΩ
R <sub>DS(on)</sub> max(@V <sub>GS</sub> = 10 V)	3.6mΩ
ID	90A

Symbol



## ■ DESCRIPTION

This is suitable for the most demanding DC-DC converter application where high efficiency is to be achieved.

## ■ FEATURES

- \* R<sub>DS(on)</sub>\*Q<sub>g</sub> industry's benchmark
- \* Conduction losses reduced
- \* Switching losses reduced
- \* Low threshold device



## ■ ORDER INFORMATION

Order codes		Package	Packing
Halogen-Free	Halogen		
N/A	MOT90N03D	TO-252	2500 pieces /Reel
N/A	MOT90N03C	TO-251	70 pieces/Tube

## ■ ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V <sub>DS</sub>	Drain-source voltage (V <sub>GS</sub> = 0)	30	V
V <sub>GS</sub>	Gate-source voltage	±20	V
I <sub>D</sub> <sup>(1)</sup>	Drain current (continuous) at T <sub>C</sub> = 25°C	90	A
I <sub>D</sub>	Drain current (continuous) at T <sub>C</sub> =100°C	72	A
I <sub>DM</sub> <sup>(2)</sup>	Drain current (pulsed)	320	A
P <sub>TOT</sub>	Total dissipation at T <sub>C</sub> = 25°C	95	W
	Derating factor	0.63	W/°C
E <sub>AS</sub> <sup>(3)</sup>	Single pulse avalanche energy	350	mJ
T <sub>J</sub> T <sub>stg</sub>	Operating junction temperature Storage temperature	-55 to 175	°C

## ■ THERMAL DATA

Symbol	Parameter	Value	Unit
R <sub>thj-case</sub>	Thermal resistance junction-case max	1.58	°C/W
R <sub>thj-amb</sub>	Thermal resistance junction-ambient max	100	°C/W
T <sub>j</sub>	Maximum lead temperature for soldering purpose	275	°C

1. Value limited by wire bonding
2. Pulse width limited by safe operating area
3. Starting T<sub>j</sub> = 25°C, I<sub>D</sub> = 40A, V<sub>DD</sub> = 15V

■ ELECTRICAL CHARACTERISTICS ( $T_c = 25^\circ\text{C}$ , unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$I_D = 250\mu\text{A}, V_{GS} = 0$	30			V
$I_{\text{DSS}}$	Zero gate voltage drain current ( $V_{GS} = 0$ )	$V_{DS} = 30\text{V}$			1	$\mu\text{A}$
		$V_{DS} = 30\text{V}, T_c = 125^\circ\text{C}$			10	$\mu\text{A}$
$I_{GSS}$	Gate body leakage current ( $V_{DS} = 0$ )	$V_{GS} = \pm 20\text{V}$			$\pm 100$	nA
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1			V
$R_{DS(\text{on})}$	Static drain-source on resistance	$V_{GS} = 10\text{V}, I_D = 40\text{A}$		3.6	4.5	$\text{m}\Omega$
		$V_{GS} = 5\text{V}, I_D = 40\text{A}$		5.6	8	
$C_{iss}$	Input capacitance	$V_{DS} = 25\text{V}, f = 1\text{MHz}, V_{GS} = 0$		2805		pF
$C_{oss}$	Output capacitance			549		pF
$C_{rss}$	Reverse transfer capacitance			76		pF
$Q_g$	Total gate charge	$V_{DD} = 15\text{V}, I_D = 80\text{A}$		22	32	nC
$Q_{gs}$	Gate-source charge	$V_{GS} = 5\text{V}$		10		nC
$Q_{gd}$	Gate-drain charge	(see Figure 13)		7		nC
$R_G$	Gate input resistance	f=1MHz Gate Bias Bias=0 Test Signal Level=20mV open drain		1.2		$\Omega$
$t_{d(\text{on})}$ $t_r$	Turn-on delay time Rise time	$V_{DD} = 15\text{V}, I_D = 40\text{A}, R_G = 4.7\Omega, V_{GS} = 5\text{V}$ (see Figure 12)		19		ns
				135		ns
$t_{d(\text{off})}$ $t_f$	Turn-off delay time Fall time	$V_{DD} = 15\text{V}, I_D = 40\text{A}, R_G = 4.7\Omega, V_{GS} = 5\text{V}$ (see Figure 12)		24		ns
				33		ns
$I_{SD}$	Source-drain current				80	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)				320	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 40\text{A}, V_{GS} = 0$			1.3	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 80\text{A}, di/dt = 100\text{A}/\mu\text{s}$		36		ns
$Q_{rr}$	Reverse recovery charge	$V_{DD} = 19\text{V}, T_j = 150^\circ\text{C}$		32		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current	(see Figure 15)		1.8		A

1. Pulse width limited by safe operating area
2. Pulsed: pulse duration=300 $\mu\text{s}$ , duty cycle 1.5%

## ■ TYPICAL CHARACTERISTICS

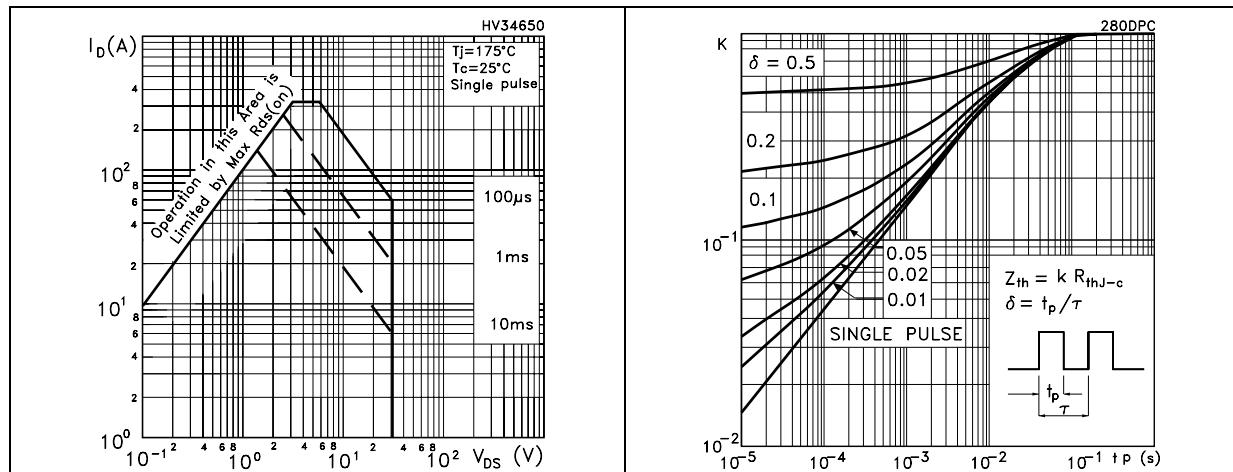


Figure 1. Safe operating area

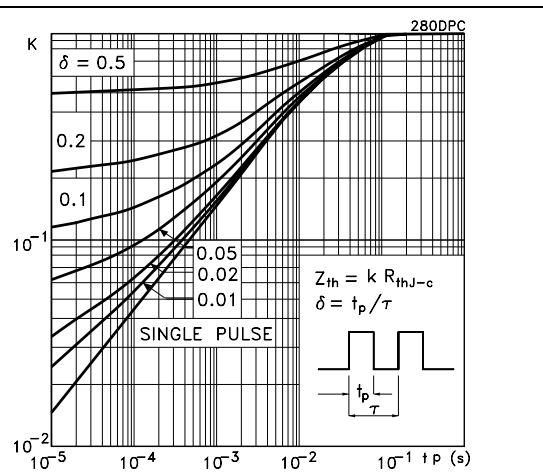


Figure 2. Thermal impedance

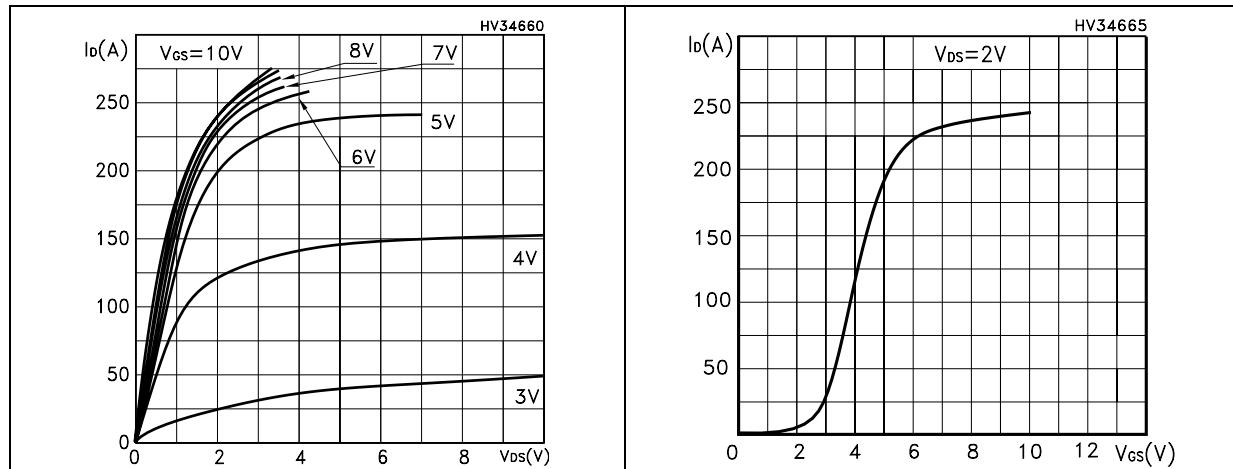


Figure 3. Output characteristics

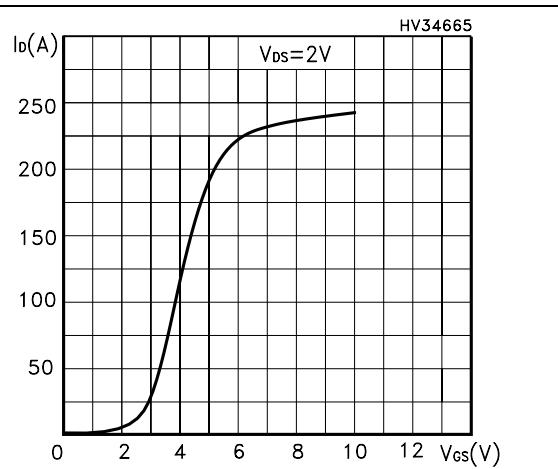


Figure 4. Transfer characteristics

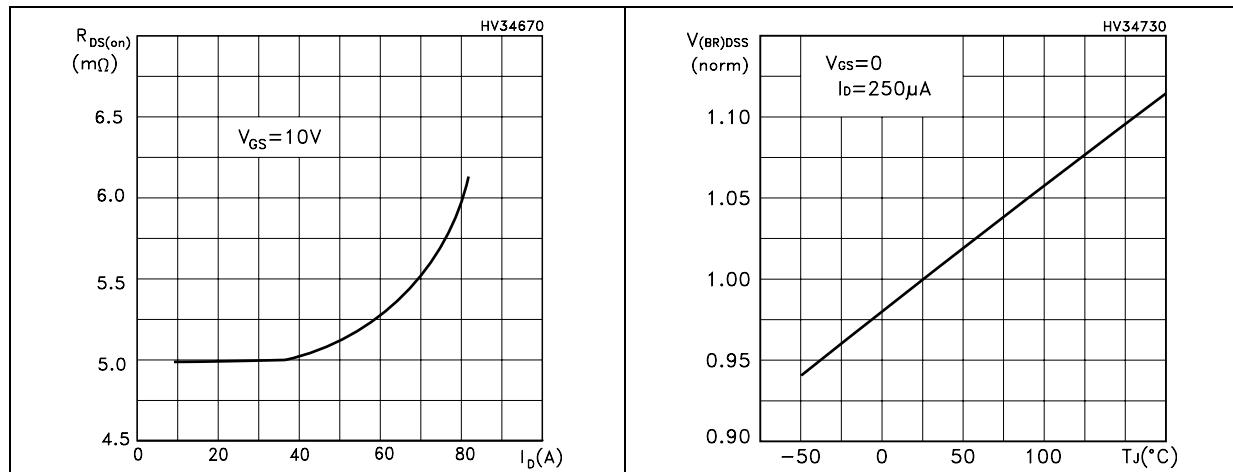
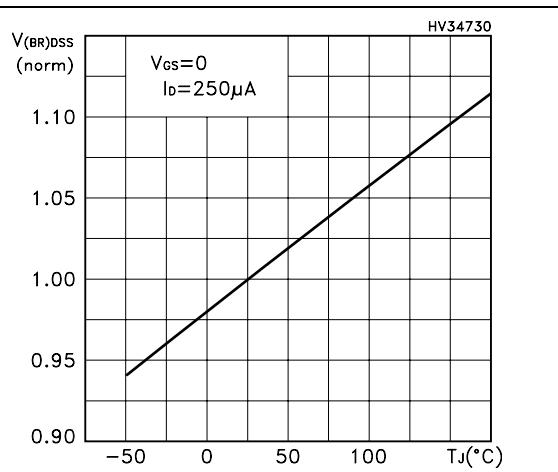


Figure 5. Static drain-source on resistance


 Figure 6. Normalized  $B_{VDSS}$  vs temperature

## ■ TYPICAL CHARACTERISTICS

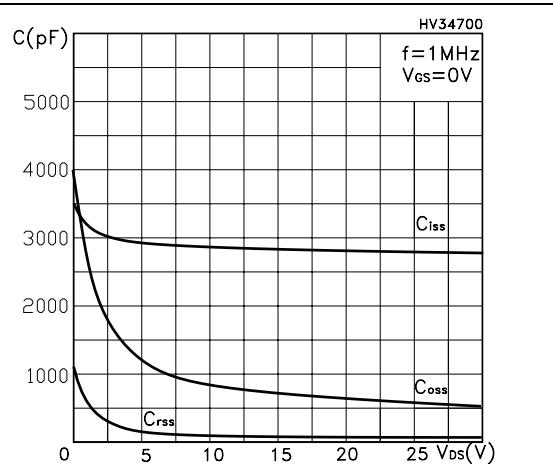
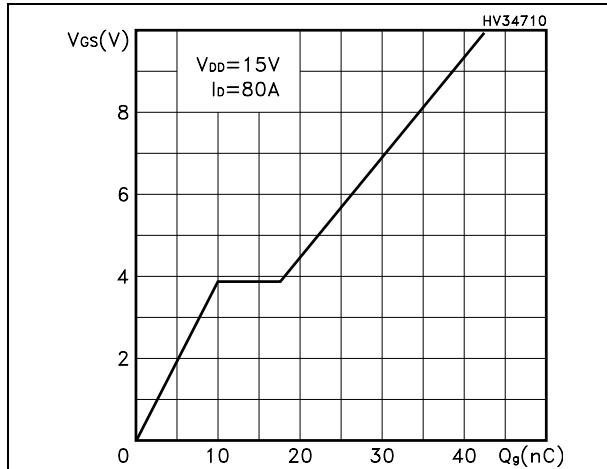


Figure 7. Gate charge vs gate-source voltage    Figure 8. Capacitance variations

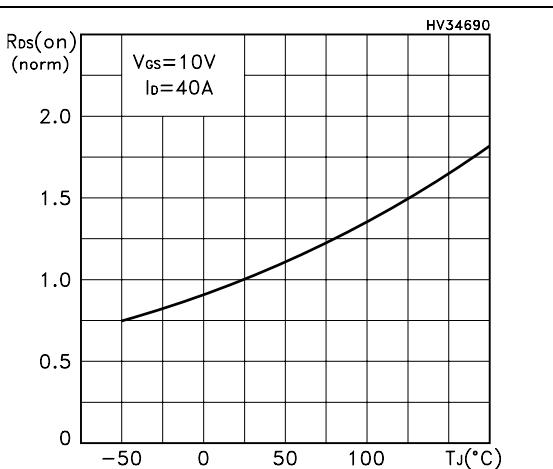
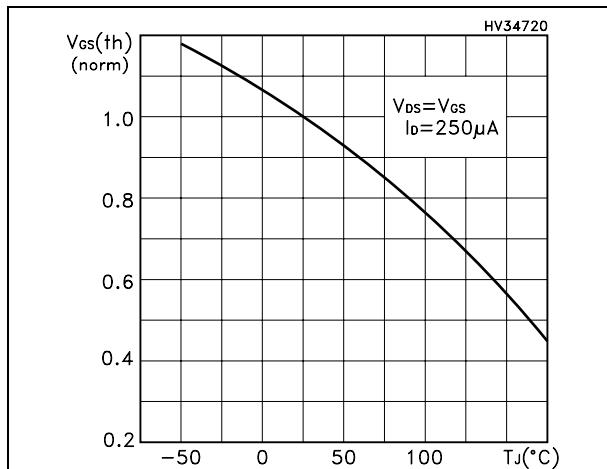


Figure 9. Normalized gate threshold voltage vs temperature

Figure 10. Normalized on resistance vs temperature

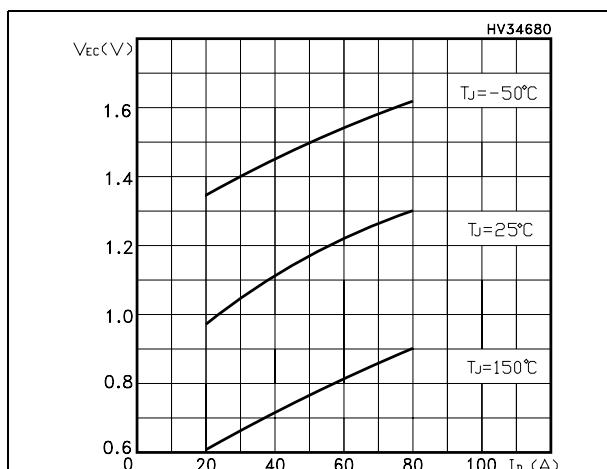
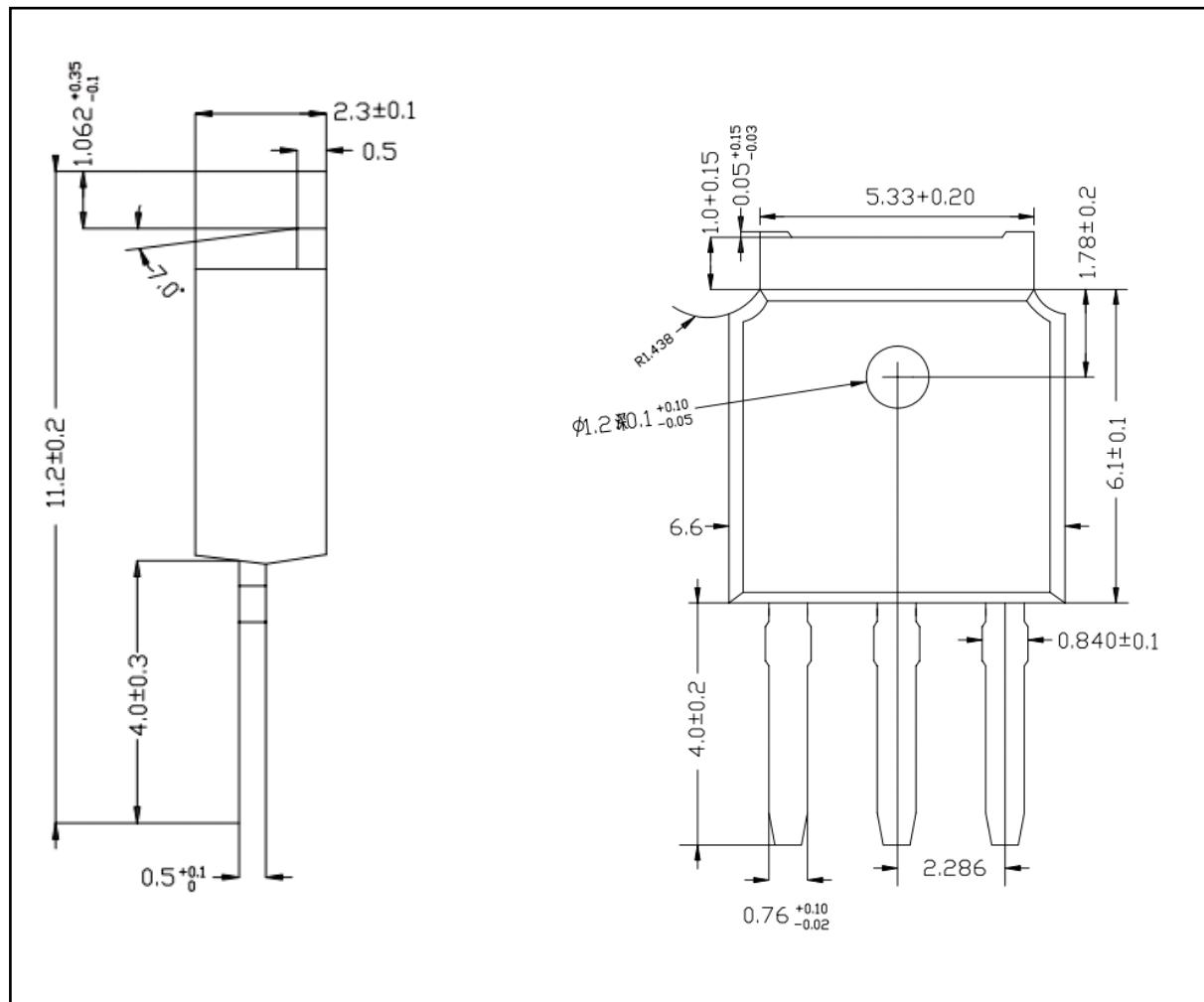


Figure 11. Source-drain diode forward characteristics

## ■ TO-251 PACKAGE OUTLINE DIMENSIONS



## ■ TO-252 PACKAGE OUTLINE DIMENSIONS

